



深圳市泰河电子有限公司

SHENZHEN TH ELECTRONICS CO;LTD

产品确认书

Product Confirmation

CUSTOMER: _____

Product :

声表面谐振器

Frequency:

R154M

Model:

F-11 DIP

DATE: _____

承认后请寄回一份

PLS SEND BACK ONE COPY TO US AFTER YOUR APPROVAL

| 承认结果 CONCLUSION | 客户签名 SIGNATURE | 客户承认章 STAMP | 日期 DATE | 备注 REMARK |
|--------------------|-------------------|----------------|------------|--------------|
| 合格 ACCEPT | | | | |
| 不合格 REJECT | | | | |

制表: 刘小姐 _____

审核: _____

(公章)

尊敬的客户: 请您抽出一点时间, 在7-10个工作日内将承认书回签, 若未回签, 以视默认. 谢谢合作!

1. SCOPE

This specification is applied to a SAW resonator designed for the stabilization of transmitters such as garage door openers and security transmitters.

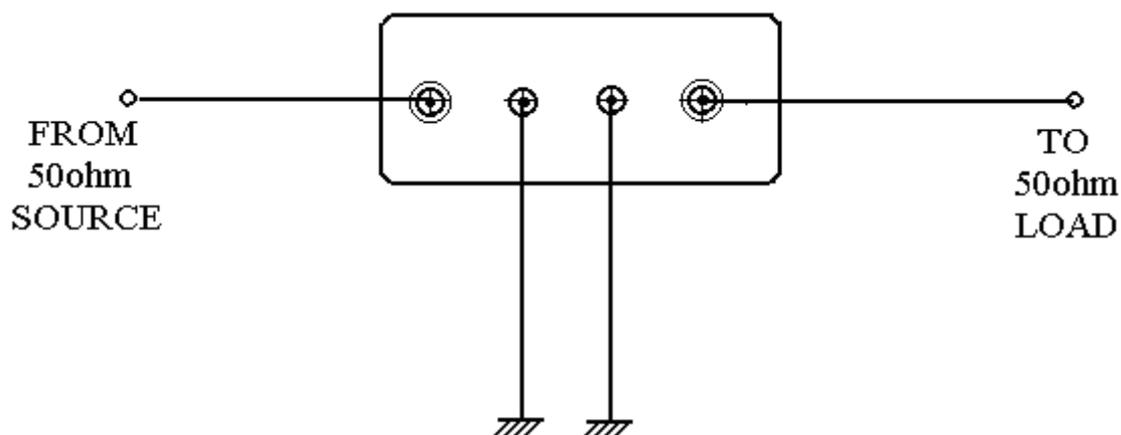
2. ELECTRICAL SPECIFICATION

| | |
|-----------------------|----------------|
| DC Voltage VDC | 30V |
| AC Voltage Vpp | 10V50Hz/60Hz |
| Operation temperature | -40°C to +85°C |
| Storage temperature | -45°C to +85°C |
| RF Power Dissipation | 0dBm |

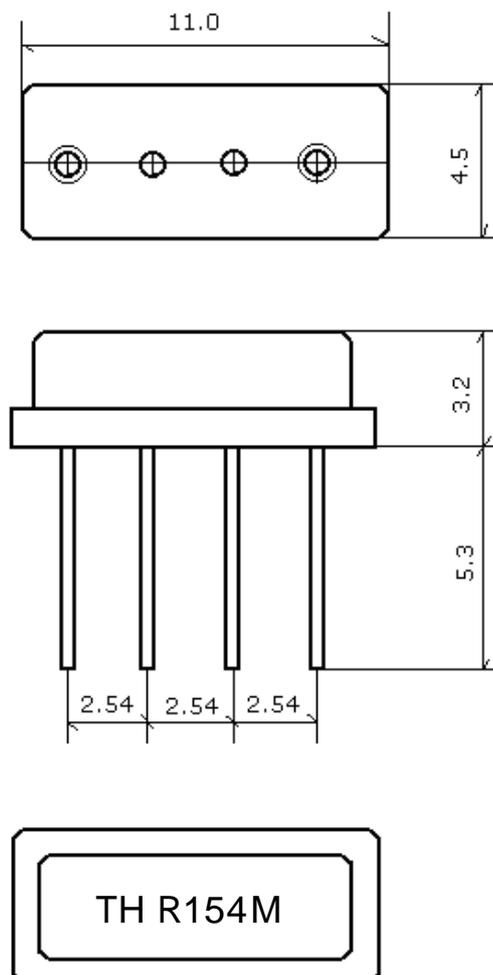
2.2 Electronic Characteristics

| Item | Unites | Minimum | Typical | Maximum |
|-------------------------------|-------------------------|---------------------|---------|---------|
| Center Frequency | MHz | 153.925 | 154.000 | 154.075 |
| Insertion Loss | dB | | 2.2 | 2.5 |
| Quality Factor Unload Q | | 14000 | 14500 | |
| 50 Ω Loaded Q | | 3000 | 4000 | |
| Temperature | Turnover Temperature | °C | 10 | 25 |
| Stability | Freq.temp.Coefficient | ppm/°C ² | 0.037 | |
| Frequency Aging | | ppm/yr | <±10 | |
| DC. Insulation Resistance | MΩ | 1.0 | | |
| RF Equivalent RLC Model | Motional Resistance R1 | Ω | 28 | 30 |
| | Motional Inductance L1 | μH | 532.63 | |
| | Motional Capacitance C1 | fF | 2.0053 | |
| Transducer Static Capacitance | pF | | 2.6 | |

3. TEST CIRCUIT



4. DIMENSION



5. ENVIRONMENTAL CHARACTERISTICS

5-1 High temperature exposure

Subject the device to +85°C for 16 hours. Then release the resonator into the room conditions for 24 hours prior to the measurement. It shall fulfill the specifications in 2.2.

5-2 Low temperature exposure

Subject the device to -40°C for 16 hours. Then release the device into the room conditions for 24 hours prior to the measurement. It shall fulfill the specifications in 2.2.

5-3 Temperature cycling

Subject the device to a low temperature of -40°C for 30 minutes. Following by a high temperature of +85°C for 30 Minutes. Then release the device into the room conditions for 24 hours prior to the measurement. It shall meet the specifications in 2.2.

5-4 Resistance to solder heat

Dip the device terminals no closer than 1.5mm into the solder bath at 260°C ±10°C for 10±1 sec. Then release the device into the room conditions for 4 hours. The device shall meet the specifications in 2.2.

5-5 Solderability

Subject the device terminals into the solder bath at $245^{\circ}\text{C} \pm 5^{\circ}\text{C}$ for 5s, More than 95% area of the terminals must be covered with new solder. It shall meet the specifications in 2.2.

5-6 Mechanical shock

Drop the device randomly onto the concrete floor from the height of 1m 3 times. the device shall fulfill the specifications in 2.2.

5-7 Vibration

Subject the device to the vibration for 1 hour each in x, y and z axes with the amplitude of 1.5 mm at 10 to 55 Hz. The device shall fulfill the specifications in 2.2.

6. REMARK

6.1 Static voltage

Static voltage between signal load & ground may cause deterioration & destruction of the component. Please avoid static voltage.

6.2 Ultrasonic cleaning

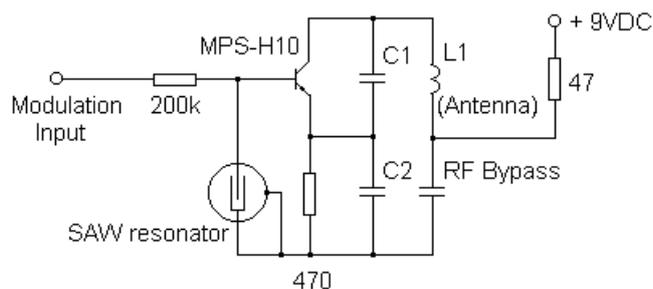
Ultrasonic vibration may cause deterioration & destruction of the component. Please avoid ultrasonic cleaning

6.3 Soldering

Only leads of component may be soldered. Please avoid soldering another part of component.

7. TYPICAL APPLICATION CIRCUITS

Typical low-power Transmitter Application



Typical Local Oscillator Application

